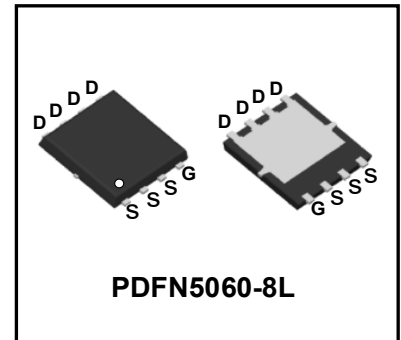


30V N-Channel Enhancement Mode Power MOSFET

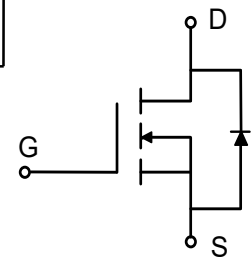
Description

WMB050N03LG4 uses Wayon's 4th generation power trench MOSFET technology that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance. This device is well suited for high efficiency fast switching applications.



Features

- $V_{DS} = 30V$, $I_D = 65A$
 $R_{DS(on)} < 5.4m\Omega @ V_{GS} = 10V$
 $R_{DS(on)} < 8m\Omega @ V_{GS} = 4.5V$
- Low $R_{DS(ON)}$
- Low Gate Charge
- 100% EAS Guaranteed



Applications

- Power Management Switches
- DC/DC Converter

Absolute Maximum Ratings ($T_A = 25^\circ C$, unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	$T_C=25^\circ C$	65
		$T_C=100^\circ C$	41
Pulsed Drain Current ¹	I_{DM}	260	A
Single Pulse Avalanche Energy ²	EAS	20	mJ
Total Power Dissipation	P_D	31.25	W
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance from Junction-to-Ambient ³	$R_{\theta JA}$	60	$^\circ C/W$
Thermal Resistance from Junction-to-Case	$R_{\theta JC}$	4	$^\circ C/W$

Electrical Characteristics ($T_J = 25^\circ C$, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics							
Drain-Source Breakdown Voltage		$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	30	-	-	V
Gate-body Leakage Current		I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
Zero Gate Voltage Drain Current	$T_J = 25^\circ C$	I_{DSS}	$V_{DS} = 30V, V_{GS} = 0V$	-	-	1	μA
	$T_J = 100^\circ C$			-	-	100	
Gate-Threshold Voltage		$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.2	1.6	2.4	V
Drain-Source On-Resistance ⁴		$R_{DS(on)}$	$V_{GS} = 10V, I_D = 20A$	-	4.2	5.4	m Ω
			$V_{GS} = 4.5V, I_D = 10A$	-	6	8	
Forward Transconductance ⁴		g_{fs}	$V_{DS} = 10V, I_D = 20A$	-	130	-	S
Dynamic Characteristics⁵							
Input Capacitance		C_{iss}	$V_{DS} = 15V, V_{GS} = 0V, f = 1MHz$	-	905	-	pF
Output Capacitance		C_{oss}		-	475	-	
Reverse Transfer Capacitance		C_{rss}		-	57	-	
Gate Resistance		R_g	$f = 1MHz$	-	1.9	-	Ω
Switching Characteristics⁵							
Total Gate Charge		Q_g	$V_{GS} = 10V, V_{DS} = 15V, I_D = 20A$	-	16	-	nC
Gate-Source Charge		Q_{gs}		-	3	-	
Gate-Drain Charge		Q_{gd}		-	3.3	-	
Turn-On Delay Time		$t_{d(on)}$	$V_{GS} = 10V, V_{DD} = 15V, R_G = 3\Omega, I_D = 20A$	-	6.3	-	ns
Rise Time		t_r		-	3.2	-	
Turn-Off Delay Time		$t_{d(off)}$		-	18	-	
Fall Time		t_f		-	3.6	-	
Body Diode Reverse Recovery Time		t_{rr}	$I_F = 20A, di/dt = 100A/\mu s$	-	10	-	ns
Body Diode Reverse Recovery Charge		Q_{rr}		-	13.2	-	nC
Drain-Source Body Diode Characteristics							
Diode Forward Voltage ⁴		V_{SD}	$I_S = 20A, V_{GS} = 0V$	-	-	1.2	V
Continuous Source Current		I_S	$T_C = 25^\circ C$	-	-	65	A

Notes:

1. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)} = 150^\circ C$.
2. The EAS data shows Max. rating . The test condition is $V_{DD} = 25V, V_{GS} = 10V, L = 0.1mH, I_{AS} = 20A$.
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test.

Typical Characteristics

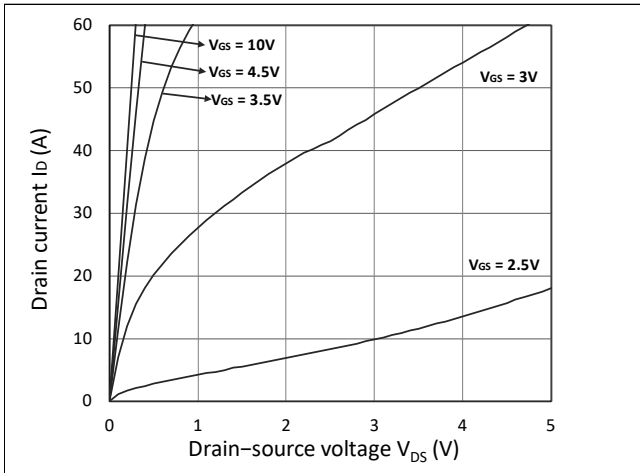


Figure 1. Output Characteristics

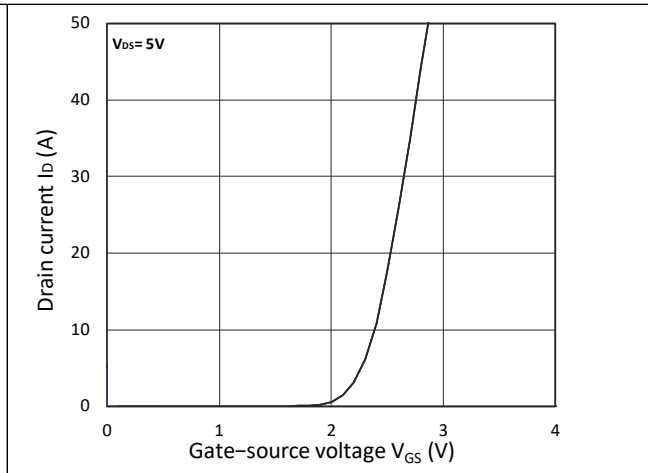


Figure 2. Transfer Characteristics

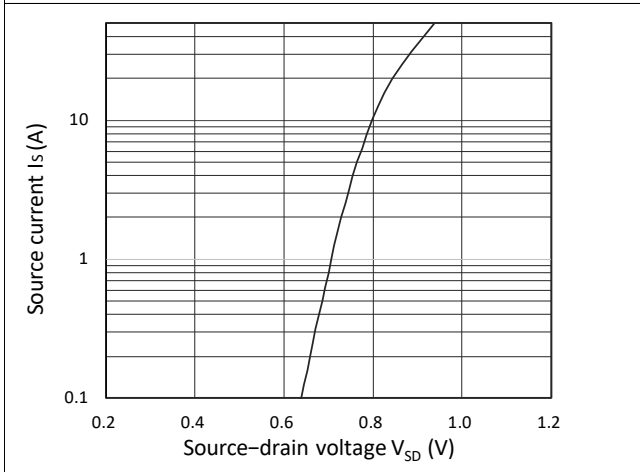


Figure 3. Forward Characteristics of Reverse

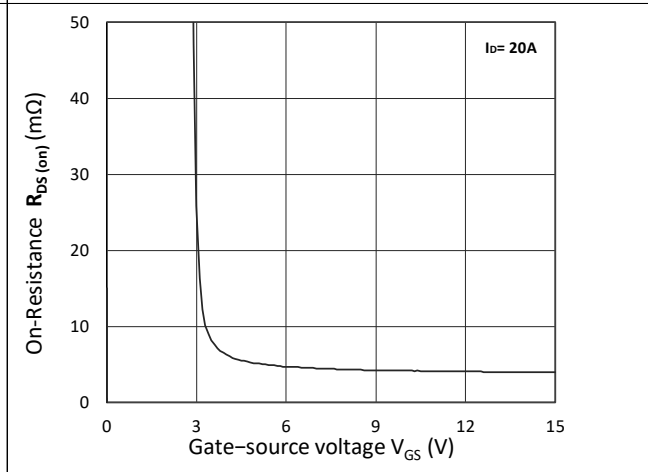


Figure 4. $R_{DS(on)}$ vs. V_{GS}

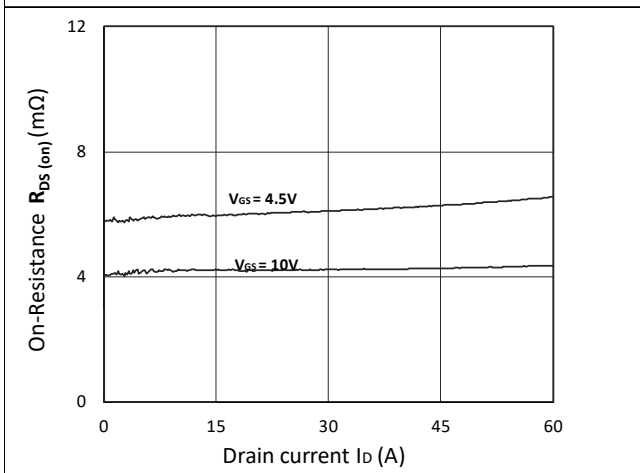


Figure 5. $R_{DS(on)}$ vs. I_D

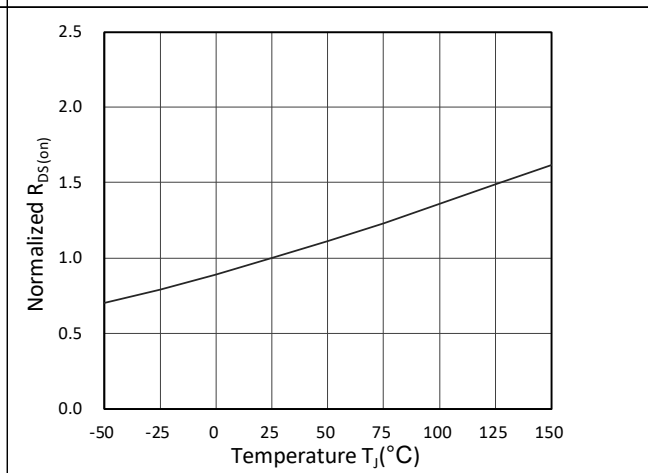


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

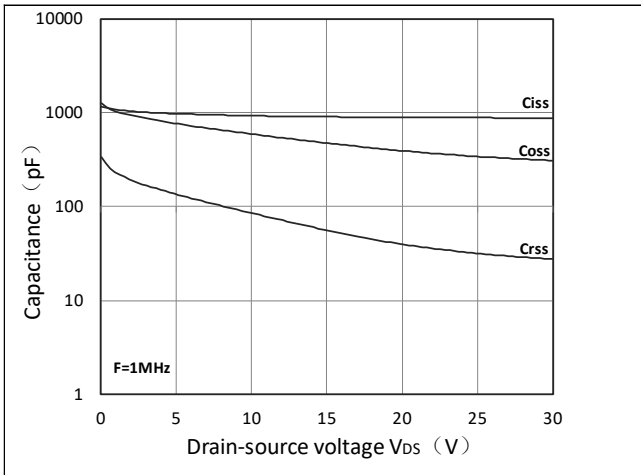


Figure 7. Capacitance Characteristics

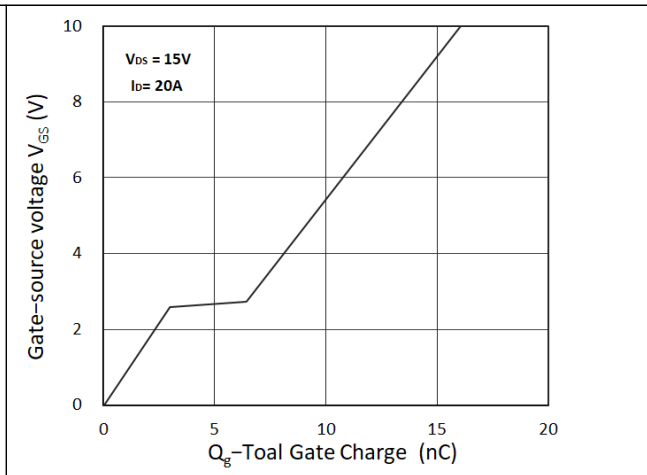


Figure 8. Gate Charge Characteristics

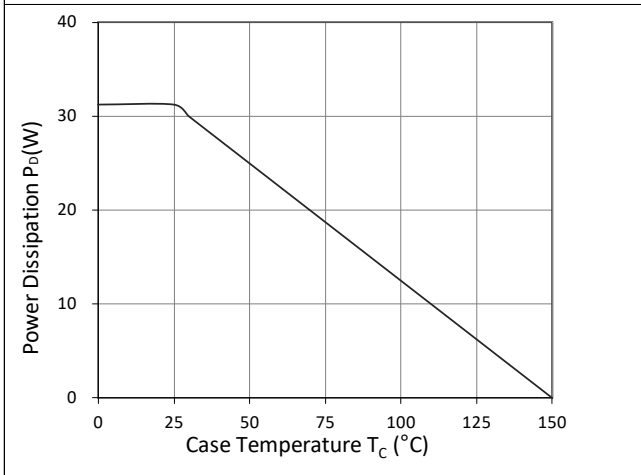


Figure 9. Power Dissipation

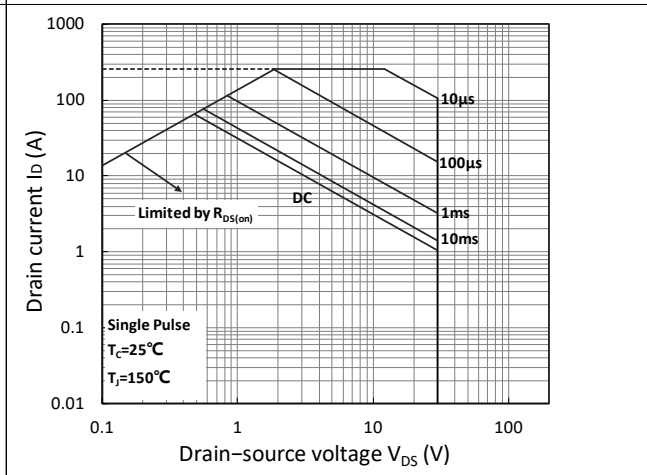


Figure 10. Safe Operating Area

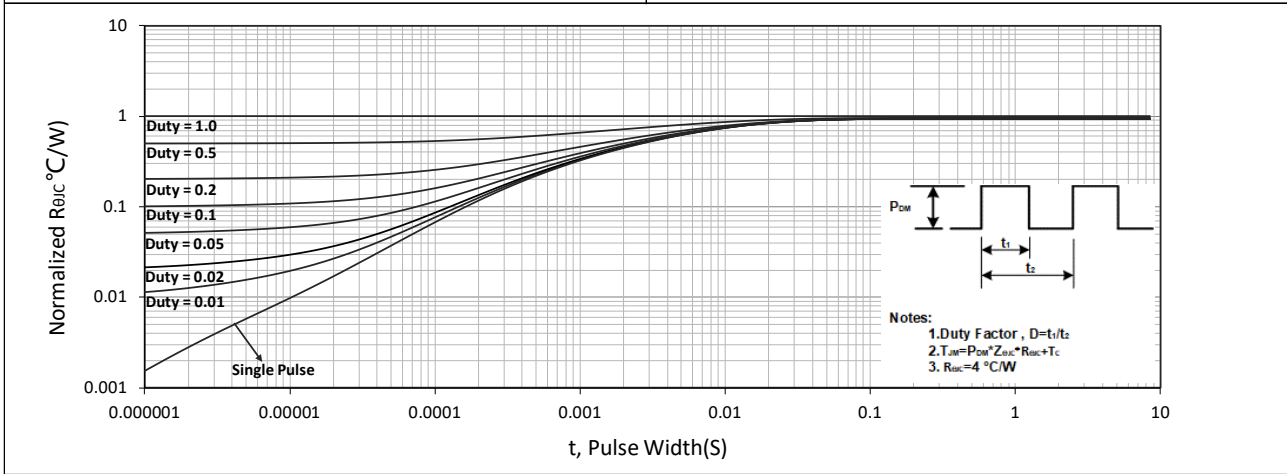


Figure 11. Normalized Maximum Transient Thermal Impedance

Test Circuit

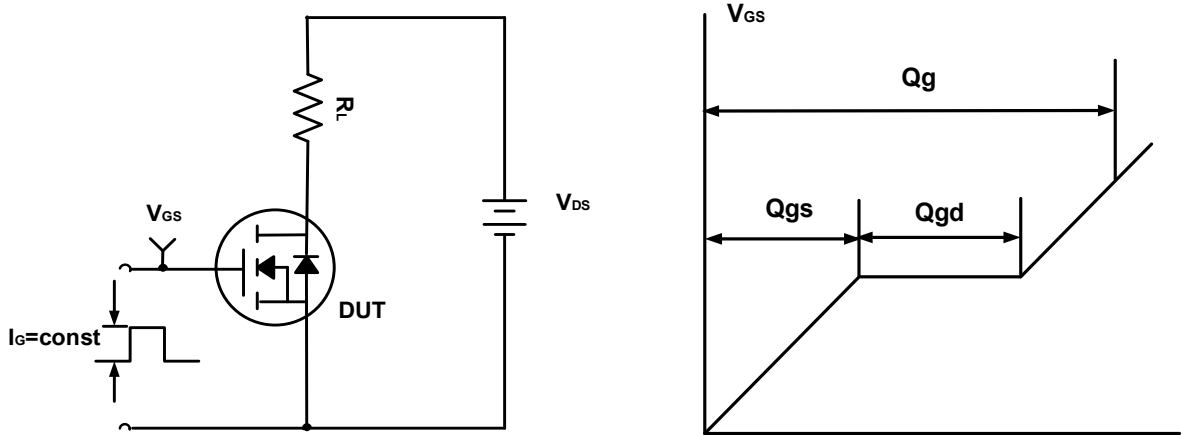


Figure A. Gate Charge Test Circuit & Waveforms

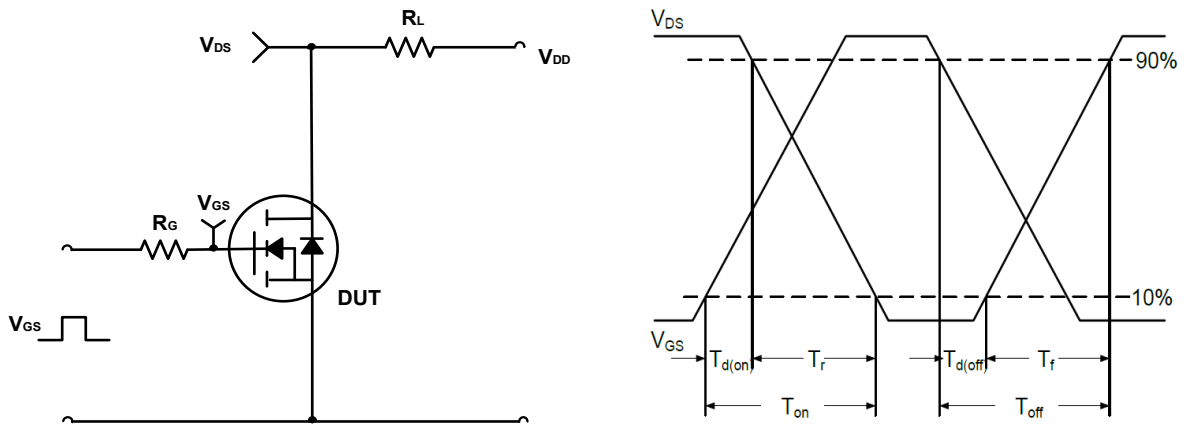


Figure B. Switching Test Circuit & Waveforms

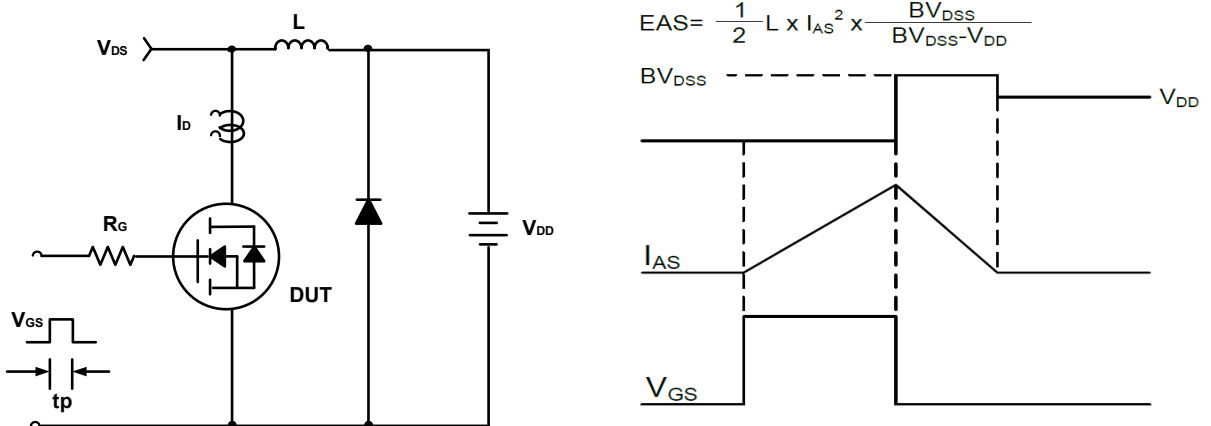
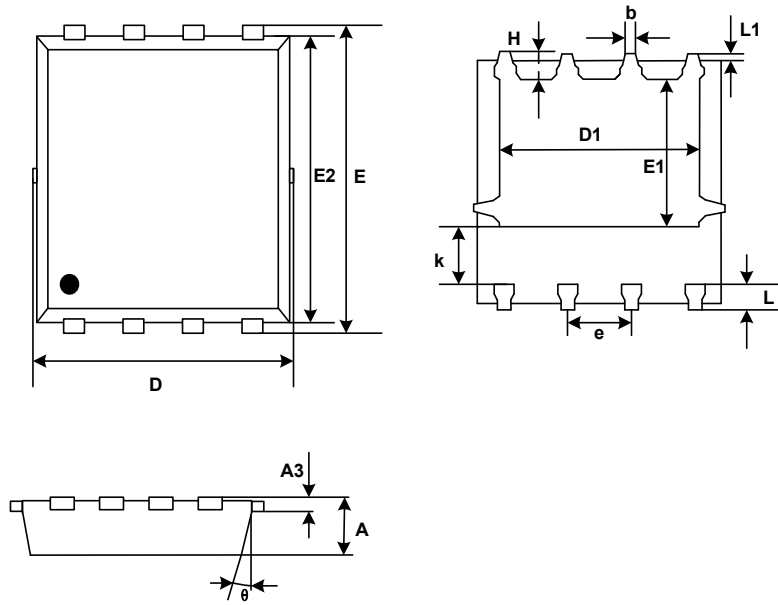


Figure C. Unclamped Inductive Switching Circuit & Waveforms

Mechanical Dimensions for PDFN5060-8L

COMMON DIMENSIONS

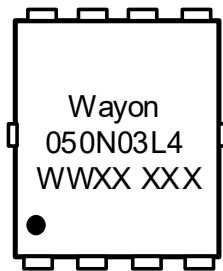


SYMBOL	MM	
	MIN	MAX
A	0.90	1.20
A3	0.15	0.35
D	4.80	5.40
E	5.90	6.35
D1	3.61	4.31
E1	3.30	3.92
E2	5.50	6.06
k	1.10	-
b	0.30	0.51
e	1.27BSC	
L	0.38	0.71
L1	0.05	0.36
H	0.38	0.71
θ	0°	12°

Ordering Information

Part	Package	Marking	Packing method
WMB050N03LG4	PDFN5060-8L	050N03L4	Tape and Reel

Marking Information



050N03L4= Device code

WWXX XXX= Date code


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